Se	arch	Notes	

Application/Control No.	Applicant(s)/Patent under Reexamination
10/809,053	ICHIKAWA ET AL.
Examiner	Art Unit

Richard Hanig

2873

SEARCHED				
Class	Subclass	Date	Examiner	
359	321, 322	8/18/2005	RH	

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
	ce Search ee printout	8/18/2005	RH

SEARCH NOT (INCLUDING SEARCH)
	DATE	EXMR
East (US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB) - see printout	8/18/2005	RH
359/323; 385/2, 8; 372/102, 12 (text only - see printout)	8/18/2005	RH
		,